

# Product Specification

# SCHOTT

## Nexterion® Glass D cleanroom cleaned (US)

Dok-Nr.:	PS-HBM-M-0009
Version:	2
Page:	1/2
Date:	23.04.2009

Product Type:	Nexterion® Glass D
Cleaning:	Cleanroom cleaned
Item Number:	1095568

### 1.1 Description

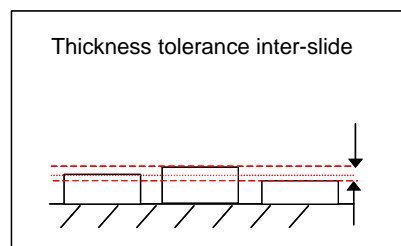
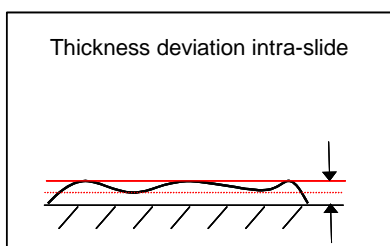
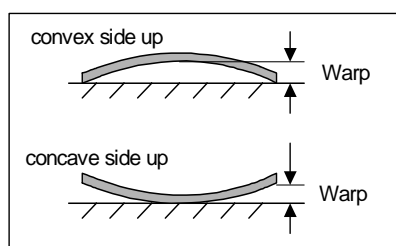
Nexterion® Glass D is a "microscope slide" sized piece of laser cut borosilicate glass. This glass is manufactured from high purity ingredients using the down draw process to produce extremely flat sheets. The borosilicate glass exhibits a high chemical resistance, as well as extremely low background fluorescence in the Cy3™ and Cy5™ emission wavelengths of 570 nm and 670 nm respectively. The slides are ultrasonically cleaned under alkaline conditions, after which each slide is checked for conformity. The approved slides are packed into plastic boxes under class 100 cleanroom conditions, and sealed in protective foil pouches containing an inert atmosphere.

### 1.2 Physical Specifications

Nexterion® Glass D is provided with laser cut edges.

Item	Specification
Thickness [mm]	1.00 mm ± 0.050 mm
Length [mm]	75.60 mm ± 0.10 mm
Width [mm]	25.0 mm ± 0.10 mm
Flatness* [mm]	≤ 0.050 mm
Roughness	typical values below 1 nm (RMS)
Transmittance	in the visible light range: > 90 %

\*Flatness = summary effect of thickness deviation (intra-slide) and warp (concave, convex).



	generated by	reviewed by	reviewed by	reviewed by	authorized by
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Date		23.04.2009	23.04.2009		23.04.2009

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### 1.3 Surface Specification

Item	Specification	Admissible count
Cleanliness	< 25 surface defects ( $\geq 20 \mu\text{m}$ )	
	visual inspection under oblique illumination	
Elongated defects (e.g. scratches)	Width $\leq 50 \mu\text{m}$ ; Length $\leq 2 \text{ mm}$	Ignore
	Width $> 50 \mu\text{m}$ ; Length $> 2 \text{ mm}$	None
Spot type defects (e.g. open bubbles, digs, chips, dross, drip, tos, bos)	$< 100 \mu\text{m}$	Ignore
	$> 100 \mu\text{m}$	None
Edge chips	Length $\leq 100 \mu\text{m}$ ; Width $\leq 100 \mu\text{m}$	Ignore
	Length $> 100 \mu\text{m}$ ; Width $> 100 \mu\text{m}$	None
Crack	Visible	None

### 1.4 Contamination

Item	Specification	Admissible count
Finger prints		None
	$< 20 \mu\text{m}$	Ignore
Particles	$20 \mu\text{m} \leq x \leq 50 \mu\text{m}$	10
	$> 50 \mu\text{m}$	None

In rare cases, abrasion particles from the box material may appear on the slide caused by the transportation process. These particles can be removed by carefully applying a clean stream of nitrogen.

#### For technical assistance please contact:

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